FCC REPORT

Report No: CCIS181205406

Applicant: Sun Cupid Technology (HK) Ltd.

Address of Applicant: 16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan,

Kowloon, Hong Kong.

Equipment Under Test (EUT)

Product Name: LTE Smart phone

Model No.: N6201L, G4

Trade mark: NUU

FCC ID: 2ADINN6201L

Applicable standards: FCC CFR Title 47 Part 22 Subpart H FCC CFR Title 47 Part 24 Subpart E

Date of sample receipt: 14 Dec., 2018

Date of Test: 14 Dec., to 22 Dec., 2018

Date of report issued: 25 Dec., 2018

Test Result: PASS*

* In the configuration tested, the EUT complied with the standards specified above.

Authorized Signature:



Bruce Zhang Laboratory Manager

This report details the results of the testing carried out on one sample. The results contained in this test report do not relate to other samples of the same product and does not permit the use of the CCIS product certification mark. The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report.

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Report No: CCIS181205406

2. Version

Version No.	Date	Description
00	25 Dec., 2018	Original

Drey Chen
Report Clerk Prepared by: Date: 25 Dec., 2018

Reviewed by: 25 Dec., 2018 Date:

Project Engineer





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4. Test Summary

Test Item	Section in CFR 47	Result
RF Exposure (SAR)	Part 1.1307 Part 2.1093	Passed* (Please refer to SAR Report)
RF Output Power	Part 2.1046 Part 22.913 (a)(2) Part 24.232 (c)	Pass
Peak-to-Average Ratio	Part 24.232(d)	Pass
Modulation Characteristics	Part 2.1047	Pass
99% & -26 dB Occupied Bandwidth	Part 2.1049 Part 22.917 Part 24.238	Pass
Spurious Emissions at Antenna Terminal	Part 2.1051 Part 22.917 (a) Part 24.238 (a)	Pass
Field Strength of Spurious Radiation	Part 2.1053 Part 22.917 (a) Part 24.238 (a)	Pass
Out of band emission, Band Edge	Part 22.917 (a) Part 24.238 (a)	Pass
Frequency stability vs. temperature	Part 22.355 Part 24.235 Part 2.1055(a)(1)(b)	Pass
Frequency stability vs. voltage	Part 22.355 Part 24.235 Part 2.1055(d) (2)	Pass
Pass: The EUT complies with the essential re	quirements in the standard.	



Report No: CCIS181205406

5. General Information

5.1 Client Information

Applicant:	Sun Cupid Technology (HK) Ltd.
Address:	16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan, Kowloon, Hong Kong.
Manufacturer	Sun Cupid Technology (HK) Ltd.
Address:	16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan, Kowloon, Hong Kong.
Factory:	SUNCUPID (ShenZhen) Electronic Ltd
Address:	Baolong Industrial City, Longgang District, Shenzhen Hi-Tech Road, Building 1, A 7, China.

5.2 General Description of E.U.T.

Product Name:	LTE Smart phone		
Model No.:	N6201L, G4		
Operation Frequency range:	BC 0: 824.70MHz-848.31MHz BC 1: 1851.25MHz-1908.75MHz		
Modulation type:	1×RTT: BPSK, QPSK, OQPSK, HPSK 1×EVDO: BPSK, QPSK, 8PSK, 16-QAM		
Antenna type:	Internal Antenna		
Antenna gain:	BC 0: -1.53 dBi BC 1: -1.53 dBi		
Power supply:	Rechargeable Li-ion Battery DC 3.85V, 3750mAh		
AC adapter:	Model: HJ-FC001K7-US Input: AC100-240V, 50/60Hz, 0.6A Output: DC 5.0V, 2000mA / DC 9.0V, 2000mA		
Test Sample Condition:	The test samples were provided in good working order with no visible defects.		
Remark:	N6201L, G4 were identical inside, the electrical circuit design, layout, components used and internal wiring, with only difference being model name and for different areas, They all have two memory configurations, 1:6G(RAM) + 64G(ROM); 2: 6G(RAM) + 128G(ROM).		

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Operation Frequency List:

В	0.0	BC 1		
Channel:	Frequency (MHz)	Channel:	Frequency (MHz)	
1013	824.70	25	1851.25	
1014	824.73	26	1851.28	
383	836.49	599	1879.97	
384	836.52	600	1880	
385	836.55	601	1880.03	
776	848.28	1174	1908.72	
777	848.31	1175	1908.75	

Regards to the operating frequency range over 10 MHz, the Lowest frequency, the middle frequency, and the highest frequency of channel were selected to perform the test, and the selected channel see below:

BC 0			BC 1		
Channel No.		Frequency(MHz)	Channel No.		Frequency(MHz)
Lowest channel	1013	824.70	Lowest channel	25	1851.25
Middle channel	384	836.52	Middle channel	600	1880.00
Highest channel	777	848.31	Highest channel	1175	1908.75

5.3 Test modes

Operating Environment	t:
Temperature:	Normal: 15° C ~ 35° C, Extreme: -30° C ~ $+50^{\circ}$ C
Humidity:	20 % ~ 75 % RH
Atmospheric Pressure:	1008 mbar
Voltage:	Nominal: 3.85Vdc, Extreme: Low 3.50 Vdc, High 4.40 Vdc
Test mode:	
Communicate mode (BC 0 1×RTT)	Keep the EUT in communicating mode on BC 0 (RC3~RC5).
Data mode (BC 0 1×EV-DO Rev.0)	Keep the EUT in data communicating mode on BC 0 Rev.0 mode.
Data mode (BC 01×EV-DO Rev. A)	Keep the EUT in data communicating mode on BC 0 Rev.A mode.
Communicate mode (BC 1 1×RTT)	Keep the EUT in communicating mode on BC 1(RC3~RC5).
Data mode (BC 1 1×EV-DO Rev. 0)	Keep the EUT in data communicating mode on BC 1 Rev.0 mode.
Data mode (BC 1 1×EV-DO Rev. A)	Keep the EUT in data communicating mode on BC 1 Rev.A mode.

Remark:

- 1. Pre-scan all test modes, and found the RC3, SO55 for Cell band, RC3 and SO2 for PCS band were the worst case.
- 2. The EUT has been tested under continuous transmitting mode. Channel Low, Mid and High for each type band with rated data rate were chosen for full testing. The field strength of spurious radiation emission was measured as EUT stand-up position (H mode) and lie down position (E1, E2 mode) for these modes with power adaptor, earphone and Data cable. Just the worst case position (H mode) shown in report.



5.4 Description of Support Units

Test Equipment	Manufacturer	Model No.	Serial No.	
Simulated Station	Rohde & Schwarz	CMW500	140493	

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5.5 Measurement Uncertainty

Parameters	Expanded Uncertainty
Radiated Emission (9kHz ~ 30MHz)	4.24 dB (k=2)
Radiated Emission (30MHz ~ 1000MHz)	4.35 dB (k=2)
Radiated Emission (1GHz ~ 18GHz)	4.44 dB (k=2)
Radiated Emission (18GHz ~ 26.5GHz)	4.56 dB (k=2)
Radiated Emission (18GHz ~ 26.5GHz)	4.56 dB (k=2)

5.6 Laboratory Facility

The test facility is recognized, certified, or accredited by the following organizations:

FCC - Registration No.: 727551

Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been accredited as a testing laboratory by FCC (Federal Communications Commission). The Registration No. is 727551.

• IC - Registration No.: 10106A-1

The 3m Semi-anechoic chamber of Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been Registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 10106A-1.

CNAS - Registration No.: CNAS L6048

Shenzhen Zhongjian Nanfang Testing Co., Ltd. is accredited to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration laboratories for the competence of testing. The Registration No. is CNAS L6048.

A2LA - Registration No.: 4346.01

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 General requirements for the competence of testing and calibration laboratories. The test scope can be found as below link: https://portal.a2la.org/scopepdf/4346-01.pdf

5.7 Laboratory Location

Shenzhen Zhongjian Nanfang Testing Co., Ltd.

Address: No. B-C, 1/F., Building 2, Laodong No.2 Industrial Park, Xixiang Road,

Bao'an District, Shenzhen, Guangdong, China Tel: +86-755-23118282, Fax: +86-755-23116366

Email: info@ccis-cb.com, Website: http://www.ccis-cb.com



5.8 Test Instruments list

Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (mm-dd-yy)	Cal. Due date (mm-dd-yy)
3m SAC	SAEMC	9m*6m*6m	966	07-22-2017	07-21-2020
BiConiLog Antenna	SCHWARZBECK	VULB9163	497	03-16-2018	03-15-2019
Biconical Antenna	SCHWARZBECK	VUBA9117	359	06-22-2017	06-21-2020
Horn Antenna	SCHWARZBECK	BBHA9120D	916	03-16-2018	03-15-2019
Horn Antenna	SCHWARZBECK	BBHA9120D	1805	06-22-2017	06-21-2020
Horn Antenna	SCHWARZBECK	BBHA 9170	BBHA9170582	11-21-2018	11-20-2019
EMI Test Software	AUDIX	E3	V	ersion: 6.110919b)
Pre-amplifier	HP	8447D	2944A09358	03-07-2018	03-06-2019
Pre-amplifier	CD	PAP-1G18	11804	03-07-2018	03-06-2019
Spectrum analyzer	Rohde & Schwarz	FSP30	101454	03-07-2018	03-06-2019
EMI Test Receiver	Rohde & Schwarz	ESRP7	101070	03-07-2018	03-06-2019
Spectrum Analyzer	Agilent	N9020A	MY50510123	11-10-2018	11-09-2019
Signal Generator	Rohde & Schwarz	SMX	835454/016	03-07-2018	03-06-2019
Signal Generator	R&S	SMR20	1008100050	03-07-2018	03-06-2019
RF Switch Unit	MWRFTEST	MW200	N/A	N/A	N/A
Test Software	MWRFTEST	MTS8200	Version: 2.0.0.0		
Cable	ZDECL	Z108-NJ-NJ-81	1608458	03-07-2018	03-06-2019
Cable	MICRO-COAX	MFR64639	K10742-5	03-07-2018	03-06-2019
Cable	SUHNER	SUCOFLEX100	58193/4PE	03-07-2018	03-06-2019
DC Power Supply	XinNuoEr	WYK-10020K	1409050110020	10-31-2018	10-30-2019
Temperature Humidity Chamber	HengPu	HPGDS-500	20140828008	09-24-2018	09-23-2019
Simulated Station	Rohde & Schwarz	CMW500	140493	07-16-2018	07-15-2019



6. Test results

6.1 Conducted Output Power, ERP and EIRP

_		
Test Requirement:	FCC part 22.913(a)(2), FCC part 24.232(c)	
Test Method:	ANSI/TIA-603-D 2010	
Limit:	BC 0: 7W BC 1: 2W	
Test setup:	System simulator ATT EUT	
Test Procedure:	The transmitter output was connected to a calibrated attenuator, the other end of which was connected to the simulated station. Transmitter output power was read off in dBm.	
Test Instruments:	Refer to section 5.8 for details	
Test mode:	Refer to section 5.3 for details	
Test results:	Passed	





Measurement Data:

RF OUTPUT POWER FOR 1×RTT:

EUT	Radio	Service	Conduc	ted Output Pow	er(dBm)	Antenna	Max.	ERP
Mode	Configuration	Option	Ch.1013	Ch.384	Ch.777	Gain	ERP	Limit
Mode	(RC)	(SO)	824.70MHz	836.52MHz	848.31MHz	(dBi)	(dBm)	(dBm)
	RC1	2(Loopback)	23.90	23.95	23.94	4.50	20.47	
	RCI	55(Loopback)	24.09	24.10	24.15	-1.53	20.47	
	RC2	9(Loopback)	24.09	24.07	24.11	-1.53	20.47	
	RC2	55(Loopback)	24.09	24.09	24.15	-1.55	20.47	
		2(Loopback)	24.05	24.07	24.06			
	RC3	55(Loopback)	24.08	24.17	24.18	-1.53	20.50	
BC 0	BC 0	32(+F-SCH)	24.18	24.10	24.21	-1.55	20.50	38.45
ВСО		32(+SCH)	24.11	24.03	24.00			36.45
		2(Loopback)	24.10	24.07	24.10			
	DC4	55(Loopback)	24.16	24.09	24.16	1.50	20.51	
	RC4	32(+F-SCH)	24.08	24.12	24.19	-1.53	20.51	
		32(+SCH)	24.04	24.09	24.12			
	RC5	2(Loopback)	24.12	24.09	24.14	-1.53	20.48	
	RCS	55(Loopback)	24.12	24.11	24.14	-1.55	20.40	
EUT	Radio	Service	Conduc	ted Output Pow	er(dBm)	Antenna	Max.	EIRP
Mode	Configuration	Option	Ch.25	Ch.600	Ch.1175	Gain	EIRP	Limit
Wode	(RC)	(SO)	1851.25MHz	1880MHz	1908.75MHz	(dBi)	(dBm)	(dBm)
	RC1	2(Loopback)	23.43	23.44	23.59	-1.53 22.10		
	KC1	55(Loopback)	23.51	23.44	23.63	-1.55	22.10	
	RC2	9(Loopback)	23.53	23.48	23.68	-1.53	22.15	
	NOZ	55(Loopback)	23.51	23.45	23.65	-1.55	22.10	
		2(Loopback)	23.56	23.50	23.66			
	RC3	55(Loopback)	23.48	23.45	23.64	-1.53	19.98	
BC 1	IXO3	32(+F-SCH)	22.48	22.47	22.50	-1.55	19.90	33.00
ВСТ		32(+SCH)	23.48	23.52	23.60			33.00
		2(Loopback)	23.30	23.46	23.64			
	RC4	55(Loopback)	23.53	23.51	23.63	-1.53	19.96	
	NO4	32(+F-SCH)	23.46	23.14	23.22	-1.00	13.30	
		32(+SCH)	23.45	23.43	23.63			
	RC5				1	1		l
		2(Loopback)	23.58	23.52	23.67	-1.53	22.11	

Note: $EIRP(dBm) = Burst \ Average \ power(dBm) + Antenna \ Gain(dBi).$ ERP(dBm) = EIRP(dBm) - 2.15(dB).



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RF OUTPUT POWER FOR CDMA2000 1×EV-DO Rev.0:

EUT Mode	FTAP Rate	RTAP Rate	Channel	Frequency (MHz)	Conducted Output Power(dBm)	Antenna Gain (dBi)	Max. ERP (dBm)	ERP Limit (dBm)
	207 21.650		1013	827.70	24.14			
BC 0	307.2kbps (2slot,QPSK)	153.6kbps	384	836.52	24.18	-1.53	20.53	38.45
	(28101,QP3K)		777	848.31	24.21			
EUT Mode	FTAP Rate	RTAP Rate	Channel	Frequency (MHz)	Conducted Output Power(dBm)	Antenna Gain (dBi)	Max. EIRP (dBm)	EIRP Limit (dBm)
	207 Okhaa		25	1851.25	23.44			
BC 1	307.2kbps (2slot,QPSK)	153.6kbps	600	1880.00	23.51	-1.53	22.03	33.00
	(25101,QF3K)		1175	1908.75	23.56			

Note: EIRP (dBm) = Burst Average power (dBm) + Antenna Gain (dBi). ERP (dBm) = EIRP (dBm) - 2.15 (dB).

RF OUTPUT POWER FOR CDMA2000 1×EV-DO Rev.A:

EUT Mode	FETAP-Traffic Format	RETAP-Data Payload Size	Channel	Frequency (MHz)	Conducted Output Power(dBm)	Antenna Gain (dBi)	Max. ERP (dBm)	ERP Limit (dBm)
	307.2k,QPSK/ACK		1013	827.70	24.26			
BC 0	Channel is transmitted	4096	384	836.52	24.04	-1.53	20.58	38.45
	at all the slots		777	848.31	24.00			
EUT	FETAP-Traffic	RETAP-Data		Frequency	Conducted	Antenna	Max.	EIRP
Mode	Format	Payload Size	Channel	(MHz)	Output	Gain	EIRP	Limit
Mode	roilliat	Payload Size		(IVITIZ)	Power(dBm)	(dBi)	(dBm)	(dBm)
	307.2k,QPSK/ACK		25	1851.25	23.58			
BC 1	Channel is transmitted	4096	600	1880.00	23.38	-1.53	22.05	33.00
	at all the slots		1175	1908.75	23.47			

Note: EIRP (dBm) = Burst Average power (dBm) + Antenna Gain (dBi).

ERP (dBm) = EIRP (dBm) - 2.15 (dB).





6.2 Peak-to-Average Ratio

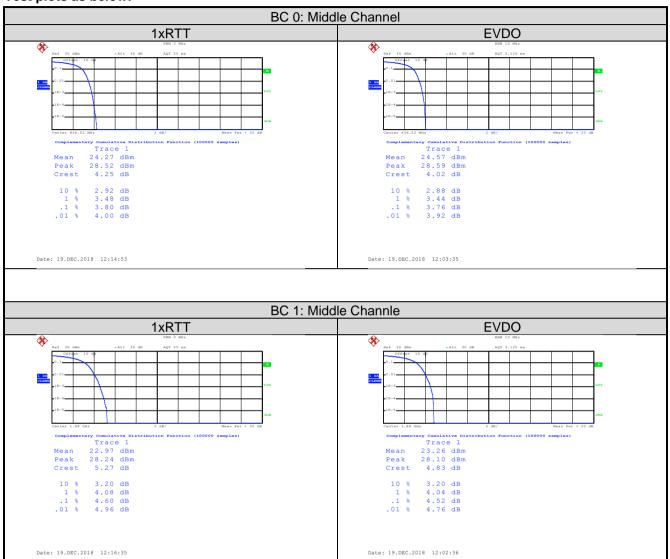
Test Requirement:	FCC part 24.232(d)
Test Method	ANSI/TIA-603-D 2010
Limit:	The peak-to-average ratio (PAR) of the transmission may not exceed 13 dB.
Test setup:	System simulator Spectrum Analyzer
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. Set the CCDF option in spectrum analyzer, RBW ≥ OBW, Set the EUT working in highest power level, measured and recorded the 0.1% as PAPR level. Repeat step 1~3 at other frequency and modulations.
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed

Band Class	Test config.	Channel No.	PAPR	Result				
	Middle channel							
BC 0	1xRTT	384	3.80	Pass				
ВСО	EVDO	384	3.76	Pass				
		Middle channel						
BC 1	1xRTT	600	4.60	Pass				
BC I	EVDO	600	4.52	Pass				
Note: Only the wor	st case mode was show	vn in report.						





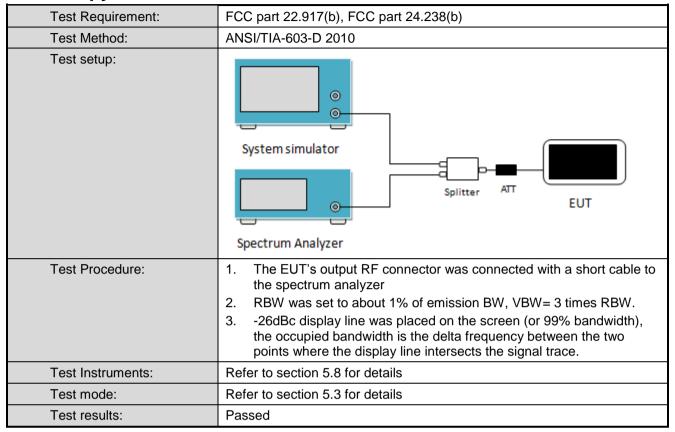
Test plots as below:







6.3 Occupy Bandwidth



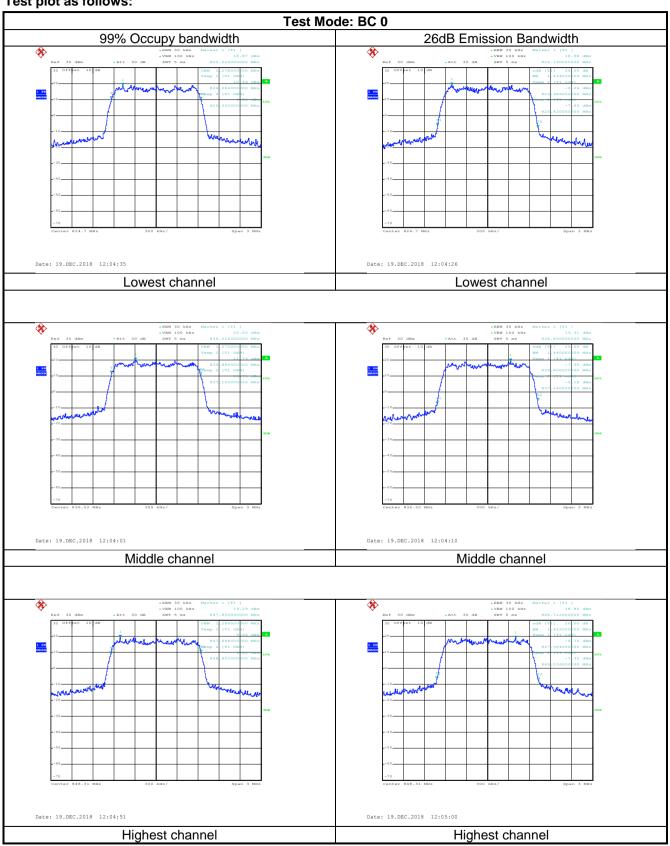
Measurement Data:

EUT Mode	Channel	Frequency (MHz)	99% Occupy bandwidth (kHz)	-26dB bandwidth (kHz)
	1013	836.52	1272	1440
BC 0	384	848.31	1284	1452
	777	824.70	1278	1434
	25	1851.25	1278	1434
BC 1	600	1880.00	1272	1440
	1175	1908.75	1272	1440



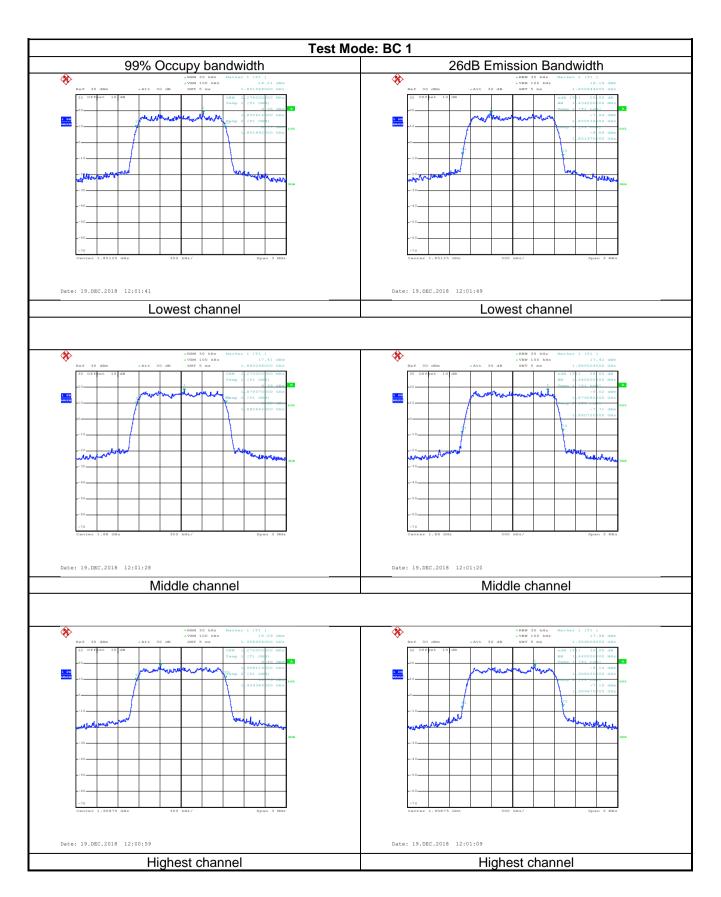


Test plot as follows:











6.4 Modulation Characteristic

According to FCC § 2.1047(d), Part 22H & 24E there is no specific requirement for digital modulation, therefore modulation characteristic is not presented.

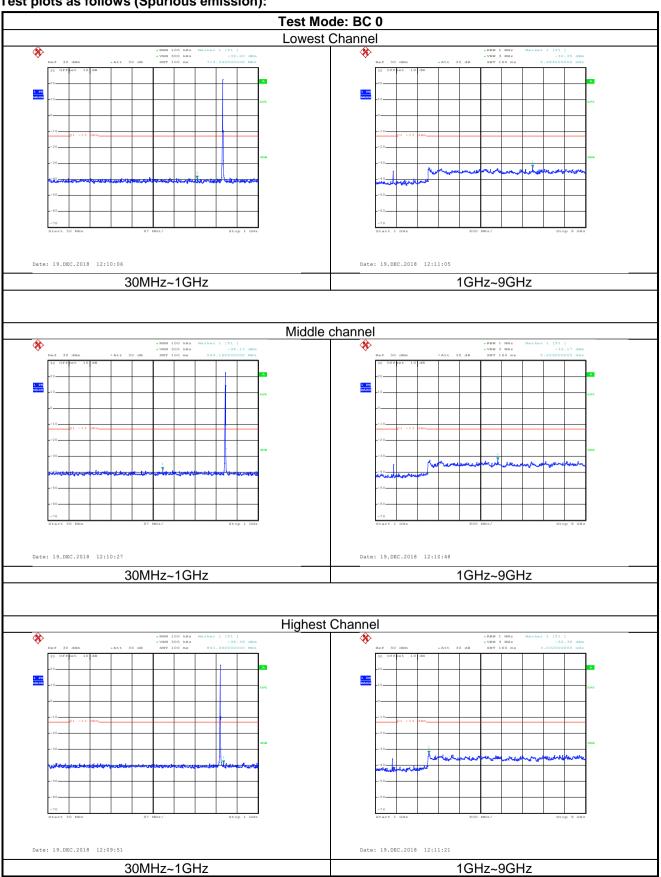
6.5 Out of band emission at antenna terminals

	on at antenna terminais
Test Requirement:	FCC part 22.917(a), FCC part 24.238(a)
Test Method:	ANSI/TIA-603-D 2010
Limit:	-13dBm
Test setup:	System simulator Splitter ATT EUT
	Spectrum Analyzer
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 100 kHz when below 1GHz, 1MHz when above 1 GHz; sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. For the out of band: Set the RBW=100 kHz, VBW=300 kHz when below 1 GHz, RBW =1 MHz, VBW=3 MHz when above 1 GHz, Start=30MHz, Stop= 10th harmonic. Band Edge Requirements: In the 1 MHz bands immediately outside and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out of band Emissions.
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed

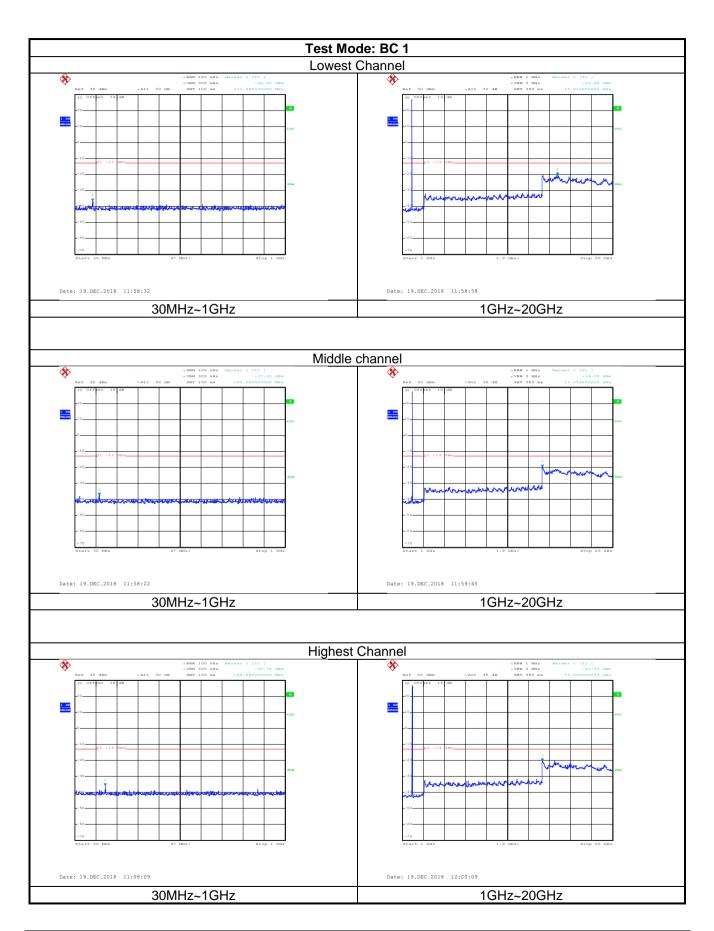




Test plots as follows (Spurious emission):



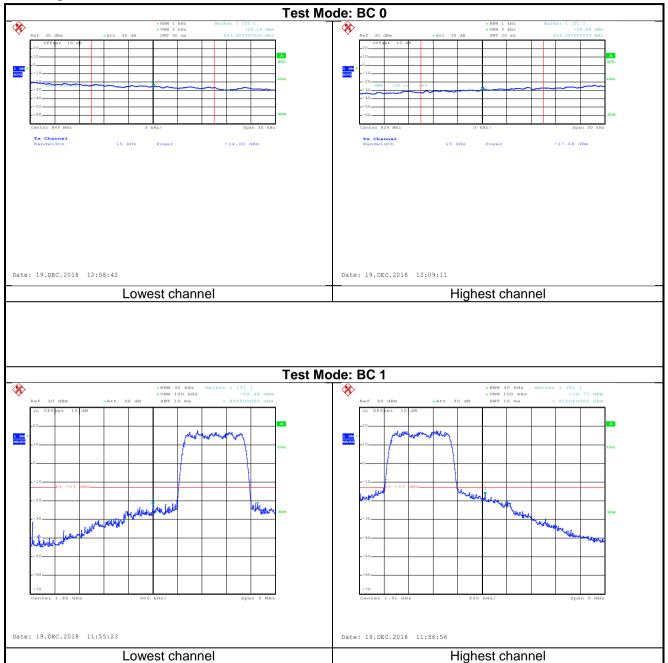








Band edge emission:





6.6 Field strength of spurious radiation measurement

Test Requirement:	FCC part 22.917(a), FCC part 24.238(a)
Test Method:	ANSI/TIA-603-D 2010
Limit:	-13dBm
Limit: Test setup:	Below 1GHz Antenna Tower Above 1GHz Above 1GHz Artenna Tower Artenna Tower Antenna Tower Antenna Tower Antenna Tower Antenna Tower Antenna Tower Antenna Tower
	Test Receiver Controller
Test Procedure:	 The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer. During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations. The frequency range up to tenth harmonic was investigated for each of three fundamental frequency (low, middle and high channels). Once spurious emission was identified, the power of the emission was determined using the substitution method. The spurious emissions attenuation was calculated as the difference between radiated power at the fundamental frequency and the spurious emissions frequency. ERP / EIRP = S.G. output (dBm) + Antenna Gain(dB/dBi) – Cable Loss (dB)
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details.
Test results:	Passed





Measurement Data (worst case):

		BC 0			
		Lowest channel			
Fraguesa (MIII-)	Spurious	Emission	Lineit (dDms)	Decult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1649.40	Vertical	-54.29			
2474.10	V	-47.53	-13.00	Pass	
3298.80	V	-48.23	-13.00	Pass	
4123.50	V	-47.27			
1649.40	Horizontal	-55.07			
2474.10	Н	-50.55	-13.00	Pass	
3298.80	Н	-50.94	-13.00	Pass	
4123.50	Н	-49.18			
		Middle channel			
Frequency (MHz)	Spurious Emission		Limit (dBm)	Result	
Frequency (Miriz)	Polarization	Level (dBm)	Limit (dBin)	Nesuit	
1673.04	Vertical	-54.37			
2509.56	V	-47.55	-13.00	Pass	
3346.08	V	-48.74	-13.00		
4182.60	V	-47.34			
1673.04	Horizontal	-55.28			
2509.56	Н	-50.35	-13.00	Pass	
3346.08	Н	-50.76	-13.00	Pass	
4182.60	Н	-49.04			
		Highest channel			
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result	
r requericy (Mir 12)	Polarization	Level (dBm)	Limit (dbin)	Result	
1696.62	Vertical	-54.41			
2544.93	V	-47.99	-13.00	Pass	
3393.24	V	-48.35	- 13.00	1 000	
4241.55	V	-47.12			
1696.62	Horizontal	-55.41]		
2544.93	Н	-50.34	-13.00	Page	
3393.24	Н	-50.26	- 13.00	Pass	
4241.55	Н	-49.34			

^{1.} The emission levels of below 1 GHz are very lower than the limit and not show in test report.





		BC 1			
		Lowest channel			
Fraguency (MUz)	Spurious	Emission	Limit (dPm)	Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3702.50	Vertical	-48.71			
5553.75	V	-42.17	-13.00	Pass	
7405.00	V	-36.55	-13.00	Pa55	
9256.25	V	-35.34			
3702.50	Horizontal	-48.75			
5553.75	Н	-41.20	40.00	Dana	
7405.00	Н	-37.04	-13.00	Pass	
9256.25	Н	-35.42			
		Middle channel			
Fraguency (MUz)	Spurious	Emission	Limit (dDm)	Dogult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3760.00	Vertical	-48.57		1	
5640.00	V	-42.69	-13.00	Pass	
7520.00	V	-36.69	-13.00		
9400.00	V	-35.55			
3760.00	Horizontal	-48.16			
5640.00	Н	-41.57	12.00	Pass	
7520.00	Н	-37.60	-13.00		
9400.00	Н	-35.56			
		Highest channel			
Fragues av (MUz)	Spurious	Emission	Limit (dDm)	Dogult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3817.50	Vertical	-48.42			
5726.25	V	-42.29	12.00	Door	
7635.00	V	-36.18	-13.00	Pass	
9543.75	V	-35.12]		
3817.50	Horizontal	-48.68			
5726.25	Н	-41.35	12.00	Dana	
7635.00	Н	-37.72	-13.00	Pass	
9543.75	Н	-35.18			

1. The emission levels of below 1 GHz are very lower than the limit and not show in test report.



6.7 Frequency stability V.S. Temperature measurement

T. (D ')	FOO D. 4.00 OFF, FOO D. 4.04 OOF, FOO D. 4.0 40FF(-)/4)/(1)
Test Requirement:	FCC Part 22.355, FCC Part 24.235, FCC Part 2.1055(a)(1)(b)
Test Method:	ANSI/TIA-6-3-D 2010
Limit:	±2.5 ppm
Test setup:	SS EUT Divider Temperature & Humidity Chamber
Test procedure:	 The equipment under test was connected to an external DC power supply and input rated voltage. RF output was connected to a frequency counter or spectrum analyzer via feed through attenuators. The EUT was placed inside the temperature chamber. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and measure EUT 25°C operating frequency as reference frequency. Turn EUT off and set the chamber temperature to -30°C. After the temperature stabilized for approximately 30 minutes recorded the frequency. Repeat step measure with 10°C increased per stage until the highest temperature of +50°C reached
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





Measurement Data (the worst channel):

Ref	ference Frequency: B	C 0 Middle c	hannel=384 chann	el=836.52MHz	
Power supplied	Tomporature (°C)	Freq	uency error	Limit (nom)	D !!
(Vdc)	Temperature (°C)	Hz	ppm	Limit (ppm)	Result
	-30	167	0.199637		
	-20	159	0.190073		
	-10	128	0.153015		
	0	139	0.166165		
3.85	10	144	0.172142	±2.5	Pass
	20	119	0.142256		
	30	123	0.147038	_	
	40	124	0.148233		
	50	131	0.156601		
Refe	rence Frequency: PC	S1900 Middle	e channel=661 cha	nnel=1880MHz	
Power supplied	Temperature (°C)	Freq	uency error	Limit (ppm)	Result
(Vdc)	Temperature (C)	Hz	ppm	Limit (ppm)	Nesuit
	-30	155	0.185291		
	-20	135	0.161383		
	-10	144	0.172142		
	0	125	0.149429		
3.85	10	121	0.144647	±2.5	Pass
	20	129	0.154210		
	30	122	0.145842		
	40	117	0.139865		
	50	128	0.153015		



6.8 Frequency stability V.S. Voltage measurement

Test Requirement:	FCC Part 22.355, FCC Part 24.235, FCC Part 2.1055(d)(2)				
Test Method:	ANSI/TIA-603-D 2010				
Limit:	±2.5ppm				
Test setup:	SS EUT Divider Temperature & Humidity Chamber				
Test procedure:	 Set chamber temperature to 25°C. Use a variable DC power source to power the EUT and set the voltage to rated voltage. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and recorded the frequency. Reduce the input voltage to specify extreme voltage variation (+/-15%) and endpoint, record the maximum frequency change. 				
Test Instruments:	Refer to section 5.8 for details				
Test mode:	Refer to section 5.3 for details				
Test results:	Passed				



Measurement Data (the worst channel):

Refe	erence Frequency: B	BC 0 Middle cl	hannel=384 channe	el=836.52MHz	
Temperature (°C)	Power supplied (Vdc)	Frequency error		Limit (nnm)	Dogult
		Hz	ppm	Limit (ppm)	Result
25	3.50	103	0.123129	±2.5	Pass
	3.85	96	0.114761		
	4.40	100	0.119543		
Ref	ference Frequency:	BC 1 Middle o	channel=600 chanr	nel=1880MHz	
Temperature (°C)	Power supplied (Vdc)	Frequency error		Limit (nnm)	Dogult
		Hz	ppm	Limit (ppm)	Result
25	3.50	127	0.151819	±2.5	Pass
	3.85	111	0.132693		
	4.40	116	0.138670		